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05/08/97
Class
Subclass
ISSUE CLASSIFICATION
SCANNED 5

6231427

UTILITY SERIAL NUMBER
PATENT DATE
MAY 15 2000
PATENT NUMBER
6231427

SERIAL NUMBER 08/853,323 FILING DATE 05/08/97 CLASS 451 SUBCLASS 451 GROUP ART UNIT 24203 EXAMINER Nguyen

APPLICANTS HOMAYOUN TALIEH, SANTA CLARA COUNTY, CA; DAVID EDWIN WELDON, SANTA CRUZ COUNTY, CA.

CONTINUING DATA***
VERIFIED THIS APPLN IS A DIV OF 08/759,172 12/03/96 PAT 5,692,947
WHICH IS A CON-OF 08/287,658 08/09/94 ABANDONED.
GN

FOREIGN/PTC APPLICATIONS***
VERIFIED
GN

CPA

FOREIGN FILING LICENSE GRANTED 10/01/97

Foreign priority claimed ☐ yes ☒ no
35 USC 119 conditions met ☒ yes ☐ no
Verified and Acknowledged 2/9/98 GN
AS FILED
STATE OR COUNTRY CA
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TITLE LINEAR POLISHER AND METHOD FOR SEMICONDUCTOR WAFER PLANARIZATION

U.S. DEPT. OF COMM./PAT. & TM—PTO-436L (Rev.12-84)

PARTS OF APPLICATION FILED SEPARATELY		Applications Examiner	
NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
01-04-01		11/3/01	
ISSUE FEE 800		Total Claims 11 Print Claim 11	
Amount Due \$1240.00	Date Paid 3-30-01	DRAWING	
Joseph H. Gilson Supervisory Patent Examiner Technical Center 1000		Sheets Drwg. 7 Figs. Drwg. 11 Print Fig. 7	
Label Area		ISSUE BATCH NUMBER A29	
PREPARED FOR ISSUE			
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SCAN 5 BW
OR DW

STAPLE

AREA

PATENT NUMBER

ORIGINAL CLASSIFICATION

CLASS	SUBCLASS
451	041

APPLICATION SERIAL NUMBER

08/853,323

APPLICANT'S NAME (PLEASE PRINT)

Talieh, et al

IF REISSUE, ORIGINAL PATENT NUMBER

INTERNATIONAL CLASSIFICATION					
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INTERNATIONAL CLASSIFICATION

ASSISTANT EXAMINER (PLEASE STAMP OR PRINT FULL NAME)

George Nguyen

PRIMARY EXAMINER (PLEASE STAMP OR PRINT FULL NAME)

FD-270
(REV. 5-91)

ISSUE CLASSIFICATION SLIP

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE